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LIST OF PATENTS AND PUBLICATIONS FOR  
APPLICANT'S INFORMATION DISCLOSURE  
STATEMENT

APPLICANT Paul Hansma, et al.

RECEIVED  
AUG 12 1996  
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(USE SEVERAL SHEETS IF NECESSARY)

FILING DATE  
9/6/96

REFERENCE DESIGNATION

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS IF APPROPRIATE	FILING DATE
jph	AA	4,935,634	6-19-90	Hansma et al		
	AB	5,164,791	11-17-92	Kubo et al.		
	AC	5,172,002	12-15-92	Marshall		
	AD	5,206,702	4-27-93	Kato et al.		
	AE	5,231,286	7-27-93	Kajimura et al.		
	AF	5,260,824	11-9-93	Okada et al.		
	AG	5,291,775	3-4-92	Gamble et al.		
	AH	5,298,975	3-29-94	Khoury et al.		
	AI	5,388,452	2-14-95	Harp et al.		
	AJ	5,394,741	3-7-95	Kajimura et al.		
	AK	5,406,833	4-18-95	Yamamoto		

FOREIGN PATENT DOCUMENTS

TRANSLATION	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	YES	NO
AL							

OTHER ART (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)

jph	AM	Drake et al.: "Imaging crystals, polymers and processes in water with the atomic force microscope," <u>Science</u> , Vol. 243, 1586 (1989) (no month)
	AN	Hansma et al.: "A new, common optical-lever based atomic force microscope," <u>J.Appl.Phys.</u> , Vol. 76, 796 (1994) (no month)
	AO	Clark et al.: "A high performance scanning force microscope head design," <u>Rev.Sci.Instrum.</u> , Vol. 64, No. 4, 904 (1993) (no month)
	AP	Baselt, et al.: "Scanned-cantilever atomic force microscope head design," <u>Rev. Sci.Instrum.</u> , Vol. 64, No. 4, 908 (1993) (no month)
	AQ	Walters, et al.: "Short cantilevers for atomic force microscopy," (no date)

- AR Hipp et al.: "A stand-alone scanning force and friction microscope," Ultramicroscopy, Vol 42-44, 1498-1503 (1992). (no month)
- AS Alexander, et al.: "An atomic resolution atomic-force microscope implemented using an optical lever" J. Appl. Phys., Vol. 65, 164-167 (1989) (no month)
- AT Binnig et al.: "Atomic Force Microscope" Phy.Rev.Let., Vol. 56, No. 9 (1986) (no month)
- AU Chalmers et al.: "Determination of tilted superlattice structure by atomic force microscopy" Appl. Phys. Let., Vol. 55, No. 24 (1989) (no month)
- AV Dietz et al.: "Atomic Force Microscopy of  $C_{60}/C_{70}$  Single-Crystal Fullerenes under Ethanol" Applied Phys., A.56, 207-210 (1993) (no month)
- AW Dietz et al.: "Molecular structure and thickness of highly oriented poly (tetrafluoroethylene) films measured by atomic force microscopy" J. of Materials Sci., (1993). (no month)
- AX Erlandsson et al.: "Atomic force microscopy using optical interferometry" J. Vac.Sci.Technol.(1988) (no month)
- AY Hansma et al.: "Scanning Tunneling Microscopy and Atomic Force Microscopy: Application to Biology and Technology" Science., Vol. 242, pgs. 209-242 (1988) (no month)
- AZ Hansma et al.: "A new optical lever based atomic force microscope" J. Appl. Phys., Vol. 76, (1994) (no month)
- BA Hillner et al.: "AFM images of dissolution and growth on a calcite crystal" Ultramicroscopy, pgs. 1387-1393 (1992) (no month)
- BB Hillner et al.: "Combined Atomic Force and Scanning Reflection Interference Contrast Microscopy; Scanning, Vol. 17, 144-147 (1995) (no month)
- BC Hillner et al.: "Combined Atomic Force and Confocal Laser Scanning Microscope" JMSA, Vol. 1, No. 3, 127-130 (1995) (no month)
- BD Kees, et al.: "Compact stand-alone atomic force microscope," Rev. Sci.Instrum., Vol 64, No. 10, (1993) (no month)
- BE Jung, et al.: ~~"Novel stationary sample atomic force microscope with beam tracking lens"~~ (no date)
- BF Marti et al.: "Atomic force microscopy of liquid covered surfaces: atomic resolution images," Appl.Phys.Let., Vol 51, No. 7 (1987). (no month)
- BG Marti, et al.: "A atomic force microscopy of an organic monolayer" Science, Vol. 239(1988) (no month)

BH	Marti et al.: "Atomic resolution force microscopy of graphite and the 'native oxide' on silicon" <u>Dept. of Physics, UCSB</u> , (1987) (no month)
BI	Marti et al.: "Atomic force microscopy and scanning tunneling microscopy with a combination atomic force microscope/scanning tunneling microscope" <u>J.Vac.Sci.Technol.</u> , A6(3)(1988) (no month)
BJ	Marti et al.: "Control electronics for atomic force microscopy" <u>Rev.Sci.Instrum.</u> , (1988) (no month)
BK	Marti et al.: "Probing surfaces with the atomic force microscope" <u>SPIE</u> , Vol. 897 (1988). (no month)
BL	Meyer et al.: "Erratum: Novel optical approach to atomic force microscopy" <u>Appl. Phys. Let.</u> Vol. 53 (1988) (no month)
BM	Putman et al.: "A theoretical comparison between interferometric and optical beam deflection technique for the measurement of cantilever displacement in AFM" <u>Ultramicroscopy</u> , pp. 1509-1513 (1992) (no month)
BO	Putman et al.: "Polymerized LB films imaged with a combined atomic force microscope-fluorescent microscope" <u>Langmuir</u> , Vol. 8, pp. 3014-3019 (1992) (no month)
BP	Putman et al.: "Immunogold labels: cell-surface markers in atomic force microscopy," <u>Ultramicroscopy</u> , Vol 48, pp. 177-182 (1993). (no month)
BQ	Radmacher et al.: "An AFM with integrated micro fluorescence optics: design and performance" <u>Ultramicroscopy</u> , pp. 968-972 (1992) (no month)
BR	Ruger et al.: "Atomic force microscopy" <u>Physics Today</u> , (1990) (no month)
BS	Walters et al.: "Atomic force microscope integrated with a scanning electron microscope for tip fabrication" <u>App. Phys. Let.</u> , Vol. 65 (1994) (no month)
BT	Radmacher et al.: "Scanning nearfield optical microscope using microfabricated probes" <u>Rev.Sci.Instrum.</u> , Vol. 65 2737 (1988) (no month)
BU	<del>Martin et al.: "Atomic force microscope mapping and probing on a sub 100-A scale" <u>J.App.Phys.</u></del> <del>(no date)</del>
BV	<del>Walters et al.: "Cantilevers for atomic force microscopy" <u>UCSB, Dept. of Physics</u></del> <del>(no date)</del>

EXAMINER

John R. Lee

DATE CONSIDERED

10-25-97

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.